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ZOEX CORPORATION ANNOUNCES A NEW GC X GC X HR-TOFMS INSTRUMENT PLATFORM

Zoex Corporation will introduce a high resolution time-of-flight mass spectrometer at the Pittsburg Conference in Orlando, March 1st – March 4th, 2010. Combined with the Zoex GC x GC thermal modulators, this state-of-the-art GC x GC x TOFMS provides the most sensitive high-resolution analytical system in the GC x GC market.

Minimum performance specifications are mass resolution 4,000 at 500 Th, mass measurement accuracy of +/- 0.002 Th; acquisition rate of 100 spectra per second; and 3+ orders of linear dynamic range. Maximum specifications are considerably higher, and will be discussed at the press conference. The device is fully supported by industry standard GC Image software, which is capable of elemental composition determinations based upon exact mass measurements.

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If you would like more information about this topic, or to schedule an interview with Ed Ledford, Jr., please visit Zoex at Booth 2277 at Pittcon 2010 or contact Lawrence Matengula on Tel +1 281 484-2828/ +1 713 854-2942 or email Lawrence@zoex.com